

Silicon Carbide (SiC) MOSFET – EliteSiC, 40 mohm, 1200 V, M1, TO-247-3L

NTHL040N120SC1

Features

- Typ. $R_{DS(on)} = 40 \text{ m}\Omega$
- Ultra Low Gate Charge (typ. Q_{G(tot)} = 106 nC)
- Low Effective Output Capacitance (typ. Coss = 140 pF)
- 100% UIL Tested
- This Device is Halide Free and RoHS Compliant with exemption 7a, Pb–Free 2LI (on second level interconnection)

Typical Applications

- UPS
- DC-DC Converter
- Boost Inverter

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	1200	V
Gate-to-Source Voltage			V _{GS}	-15/+25	V
Recommended Operation Values of Gate-to-Source Voltage	T _C < 175°C		V_{GSop}	-5/+20	٧
Continuous Drain Current $R_{\theta JC}$	Steady T _C = 25°C		I _D	60	Α
Power Dissipation $R_{\theta JC}$			P_{D}	348	W
Continuous Drain Current $R_{\theta JC}$	Steady State	T _C = 100°C	I _D	42	Α
Power Dissipation $R_{\theta JC}$			P_{D}	174	W
Pulsed Drain Current (Note 2)	T _A = 25°C		I _{DM}	240	Α
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +175	°C
Source Current (Body Diode)			I _S	34	Α
Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 23 A, L = 1 mH) (Note 3)			E _{AS}	613	mJ

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

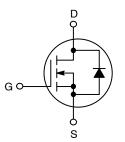
THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Note 1)	$R_{\theta JC}$	0.43	°C/W
Junction-to-Ambient (Note 1)	$R_{\theta JA}$	40	°C/W

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Repetitive rating, limited by max junction temperature.
- 3. E_{AS} of 613 mJ is based on starting $T_J = 25^{\circ}C$; L = 1 mH, $I_{AS} = 35$ A, $V_{DD} = 120$ V, $V_{GS} = 20$ V.

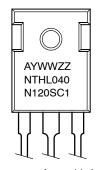
V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX
1200 V	56 m Ω @ 20 V	60 A

N-CHANNEL MOSFET





MARKING DIAGRAM



A = Assembly Location

Y = Year

WW = Work Week

ZZ = Lot Traceability

NTHL040N120SC1 = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
NTHL040N120SC1	TO-247-3LD	30 Units / Tube

ELECTRICAL CHARACTERISTICS

Parameter STIC	1	Total Constitutions		-		1114	
Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit	
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	1200	-	_	V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	I _D = 1 mA, referenced to 25°C	_	450	-	mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = 1200 \text{ V}, T_{J} = 25^{\circ}\text{C}$	-	_	100	μΑ	
		$V_{GS} = 0 \text{ V}, V_{DS} = 1200 \text{ V}, T_{J} = 175^{\circ}\text{C}$	-	_	250		
Gate-to-Source Leakage Current	I _{GSS}	$V_{GS} = +25/-15 \text{ V}, V_{DS} = 0 \text{ V}$	-	_	±1	μΑ	
ON CHARACTERISTICS							
Gate Threshold Voltage	V _{GS(th)}	$V_{GS} = V_{DS}$, $I_D = 10 \text{ mA}$	1.8	2.97	4.3	V	
Recommended Gate Voltage	V_{GOP}		-5	-	+20	V	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 20 V, I _D = 35 A, T _J = 25°C	-	39	56	mΩ	
		V _{GS} = 20 V, I _D = 35 A, T _J = 175°C	_	67	100		
Forward Transconductance	9 _{FS}	V _{DS} = 20 V, I _D = 35 A	-	20	_	S	
CHARGES, CAPACITANCES & GATE	RESISTANCE						
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 800 V	_	1781	-	pF	
Output Capacitance	C _{OSS}]	-	140	_		
Reverse Transfer Capacitance	C _{RSS}	1	-	12	_		
Total Gate Charge	Q _{G(tot)}	$V_{GS} = -5/20 \text{ V}, V_{DS} = 600 \text{ V}, I_D = 47 \text{ A}$	_	106	-	nC	
Threshold Gate Charge	Q _{G(th)}		_	16	-	1	
Gate-to-Source Charge	Q _{GS}		-	34	-		
Gate-to-Drain Charge	Q_{GD}	1	-	26	-	1	
Gate Resistance	R _G	f = 1 MHz	-	2.2	_	Ω	
SWITCHING CHARACTERISTICS							
Turn-On Delay Time	t _{d(on)}	$V_{GS} = -5/20 \text{ V}, V_{DS} = 800 \text{ V},$	_	18	_	ns	
Rise Time	t _r	$I_D = 47 \text{ A}, R_G = 4.7 \Omega,$ Inductive Load	_	41	_	1	
Turn-Off Delay Time	t _{d(off)}		_	33	_	1	
Fall Time	t _f	-	_	10.4	_		
Turn-On Switching Loss	E _{ON}	-	_	1003	_	μJ	
Turn-Off Switching Loss	E _{OFF}	1		247	_	, ,	
Total Switching Loss	E _{TOT}	1		1248	_	1	
DRAIN-SOURCE DIODE CHARACTEI							
Continuous Drain-to-Source Diode Forward Current	I _{SD}	$V_{GS} = -5 \text{ V}, T_J = 25^{\circ}\text{C}$	_	-	34	Α	
Pulsed Drain-to-Source Diode Forward Current (Note 2)	I _{SDM}	V _{GS} = -5 V, T _J = 25°C	_	-	240	A	
Forward Diode Voltage	V _{SD}	V _{GS} = -5 V, I _{SD} = 17.5 A, T _J = 25°C	_	3.8	-	V	
Reverse Recovery Time	t _{RR}	V _{GS} = -5/20 V, I _{SD} = 47 A,	_	24	-	ns	
Reverse Recovery Charge	Q _{RR}	dl _S /dt = 1000 A/μs	_	125	_	nC	
Reverse Recovery Energy	E _{REC}	1	_	8.5	_	μJ	
Peak Reverse Recovery Current	I _{RRM}	1	_	10.4	_	A	
Charge Time	t _a	-	_	12.4	_	ns	
Discharge Time	t _b	1	_	11.6	_	ns	
	u,						

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

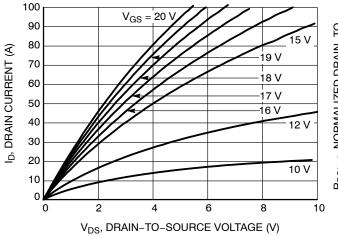


Figure 1. On-Region Characteristics

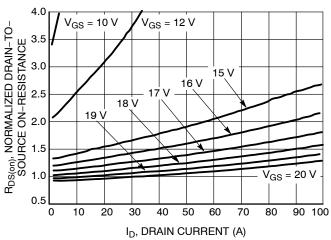


Figure 2. Normalized On–Resistance vs. Drain Current and Gate Voltage

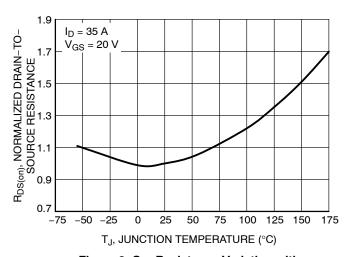


Figure 3. On–Resistance Variation with Temperature

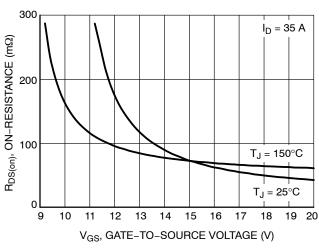


Figure 4. On–Resistance vs. Gate–to–Source Voltage

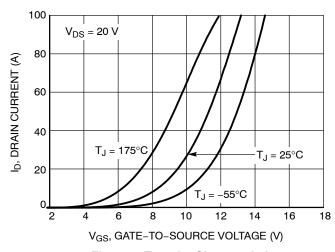


Figure 5. Transfer Characteristics

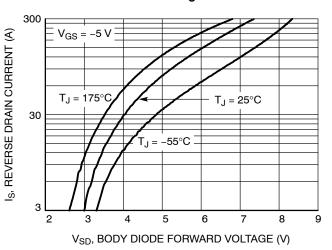


Figure 6. Diode Forward Voltage vs. Current

TYPICAL CHARACTERISTICS (CONTINUED)

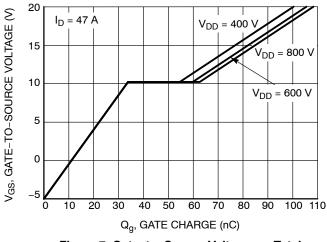


Figure 7. Gate-to-Source Voltage vs. Total Charge

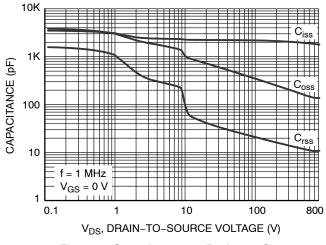


Figure 8. Capacitance vs. Drain-to-Source Voltage

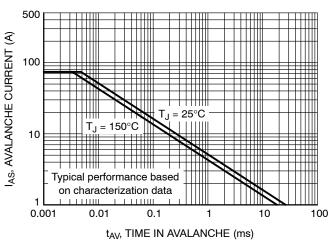


Figure 9. Unclamped Inductive Switching Capability

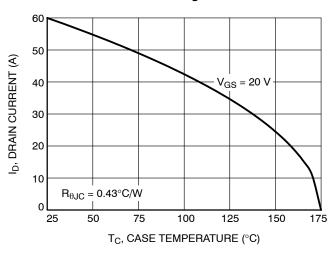


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

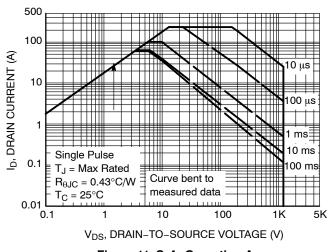


Figure 11. Safe Operating Area

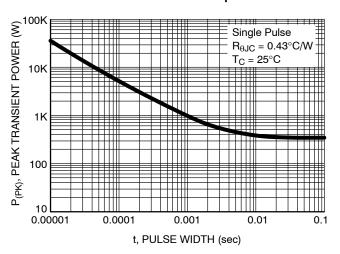


Figure 12. Single Pulse Maximum Power Dissipation

TYPICAL CHARACTERISTICS (CONTINUED)

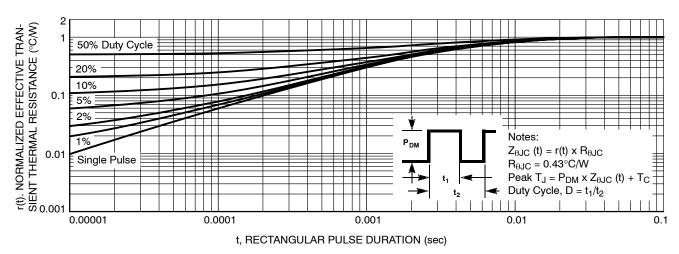
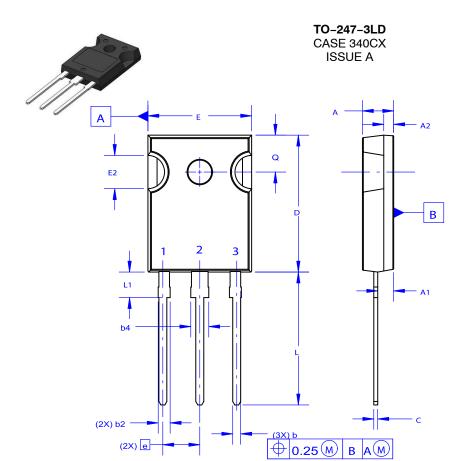
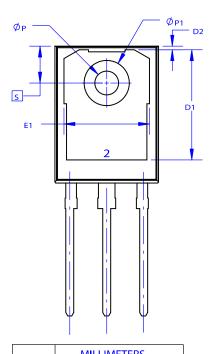


Figure 13. Junction-to-Ambient Thermal Response



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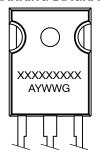


NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

 B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " =", may or may not be present. Some products may not follow the Generic Marking.

DIM	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
A 1	2.20	2.40	2.60		
A2	1.40	1.50	1.60		
D	20.32	20.57	20.82		
Е	15.37	15.62	15.87		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	19.75	20.00	20.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
E1	12.81	~	~		
Ø P 1	6.60	6.80	7.00		

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